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	28878 Annel Power Trenc	h <sup>®</sup> MC	DSFET		Nover	nber 20
30V, 16. Feature	<b>5Α, 14m</b> Ω s		General	Descrintio	n	
• Max $r_{DS(on)} = 14m\Omega$ at $V_{GS} = 10V$ , $I_D = 9.6A$ • Max $r_{DS(on)} = 17m\Omega$ at $V_{GS} = 4.5V$ , $I_D = 8.7A$ • Low Profile - 0.8 mm max in MLP 3.3X3.3		General Description This N-Channel MOSFET is a rugged gate version Fairchild Semiconductor's advanced Power Trend process. It has been optimized for power manageme applications.				
■ RoHS Compliant			Application ■ DC - DC Conversion			
	Тор В	ottom				
	8 7 6 5 D	ррр				
				D 6		3 S
1		S S Pin 1	1	D 6 D 7 D 8		3 S 2 S 1 S
1	2 3 4 G S S MLP 3.3x3.3	S S <sub>Pin 1</sub>	1	D 7		2 S
10SFE	MLP 3.3x3.3 T Maximum Ratings Τ <sub>Α</sub> = 25°C	C unless othe		D 7	Patings	2 S 1 S
IOSFE <sup>-</sup> Symbol	MLP 3.3x3.3 T Maximum Ratings т <sub>А</sub> = 25°С Раг			D 7	Ratings 30	2 S 1 S
NOSFE Symbol	MLP 3.3x3.3 T Maximum Ratings Τ <sub>Α</sub> = 25°C	C unless othe		D 7	•	2 S 1 S
NOSFE Symbol	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package	C unless othe rameter	erwise noted T <sub>C</sub> = 25°C	D 7	30	2 S 1 S
AOSFE Symbol /DS /GS	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li	C unless othe rameter	erwise noted $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$	D 7 D 8	30 ±20 16.5 38	2 S 1 S Unit
AOSFE Symbol /DS /GS	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li -Continuous	C unless othe rameter	erwise noted T <sub>C</sub> = 25°C	D 7	30 ±20 16.5 38 9.6	2 S 1 S
AOSFE Symbol /DS /GS	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li -Continuous -Pulsed	C unless othe rameter	T <sub>C</sub> = 25°C T <sub>C</sub> = 25°C T <sub>C</sub> = 25°C T <sub>A</sub> = 25°C	D 7	30 ±20 16.5 38 9.6 60	2 S 1 S Unit: V
MOSFE Symbol / <sub>DS</sub> / <sub>GS</sub>	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li -Continuous -Pulsed Power Dissipation	C unless othe rameter	T <sub>C</sub> = 25°C T <sub>C</sub> = 25°C T <sub>A</sub> = 25°C T <sub>C</sub> = 25°C T <sub>C</sub> = 25°C	D 7 D 8 (Note 1a)	30 ±20 16.5 38 9.6 60 31	2 S 1 S Unit: V
MOSFE Symbol /DS /GS D	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li -Continuous Pulsed Power Dissipation Power Dissipation	c unless othe rameter e limited) mited)	erwise noted $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$	D 7	30 ±20 16.5 38 9.6 60 31 2.1	2 S 1 S 1 S
AOSFE Symbol /os /os D Po	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li -Continuous -Pulsed Power Dissipation Power Dissipation Power Dissipation Operating and Storage Junction Tem	c unless othe rameter e limited) mited)	erwise noted $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$	D 7 D 8 (Note 1a)	30 ±20 16.5 38 9.6 60 31	2 S 1 S 1 S
MOSFE Symbol V <sub>DS</sub> V <sub>GS</sub> ID P <sub>D</sub> TJ, T <sub>STG</sub>	MLP 3.3x3.3 T Maximum Ratings T <sub>A</sub> = 25°C Par Drain to Source Voltage Gate to Source Voltage Drain Current -Continuous (Package -Continuous (Silicon li -Continuous Pulsed Power Dissipation Power Dissipation	C unless othe rameter e limited) mited) perature Rar	erwise noted $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$	D 7 D 8 (Note 1a)	30 ±20 16.5 38 9.6 60 31 2.1	2 S 1 S V V A W

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8878	FDMC8878	MLP 3.3X3.3	13 "	12 mm	3000 units

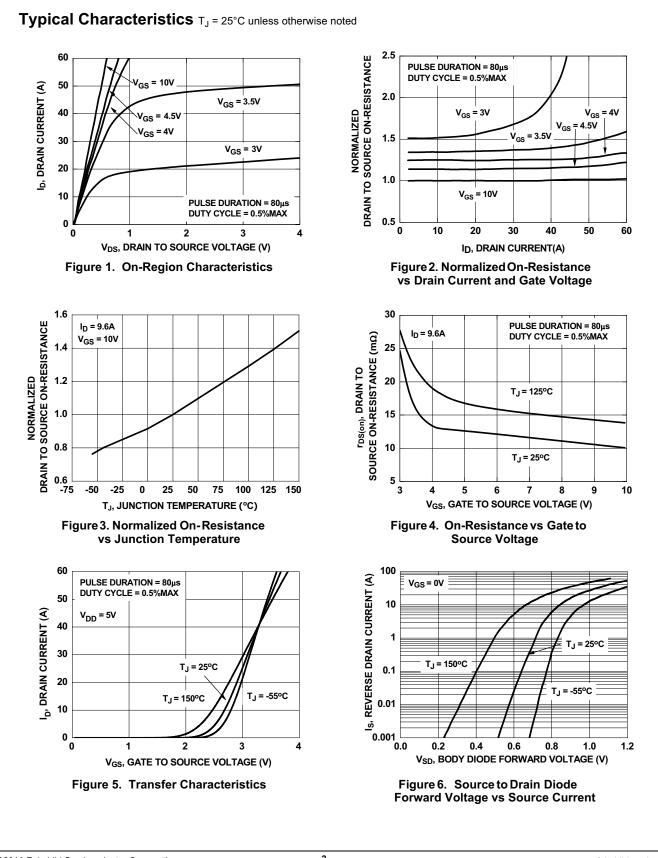
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FDMC8878
N-Channel
Power
Trench®
MOSFET

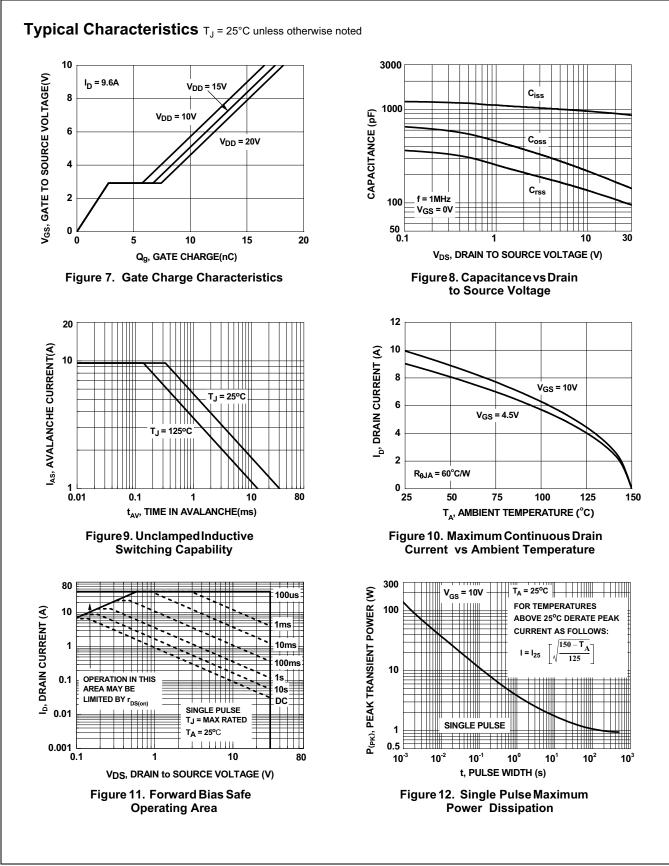
ics p Source Breakdown Voltage own Voltage Temperature ient ate Voltage Drain Current p Source Leakage Current ics p Source Threshold Voltage p Source Threshold Voltage rature Coefficient	$I_{D} = 250\mu A, V_{GS} = 0V$ $I_{D} = 250\mu A, referenced to 25°C$ $V_{DS} = 24V,$ $V_{GS} = 0V$ $T_{J} = 125°C$ $V_{GS} = \pm 20V, V_{DS} = 0V$ $V_{GS} = V_{DS}, I_{D} = 250\mu A$ $I_{D} = 250\mu A, referenced to 25°C$	30	20 20 1.7	1 100 ±100	V mV/°C μA nA
own Voltage Temperature ient ate Voltage Drain Current o Source Leakage Current ics o Source Threshold Voltage o Source Threshold Voltage	$I_{D} = 250\mu\text{A}, \text{ referenced to } 25^{\circ}\text{C}$ $V_{DS} = 24\text{V},$ $V_{GS} = 0\text{V} \qquad T_{J} = 125^{\circ}\text{C}$ $V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$ $V_{GS} = V_{DS}, I_{D} = 250\mu\text{A}$			100 ±100	mV/°C μA nA
own Voltage Temperature ient ate Voltage Drain Current o Source Leakage Current ics o Source Threshold Voltage o Source Threshold Voltage	$I_{D} = 250\mu\text{A}, \text{ referenced to } 25^{\circ}\text{C}$ $V_{DS} = 24\text{V},$ $V_{GS} = 0\text{V} \qquad T_{J} = 125^{\circ}\text{C}$ $V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$ $V_{GS} = V_{DS}, I_{D} = 250\mu\text{A}$	1		100 ±100	μA nA
o Source Leakage Current ics o Source Threshold Voltage o Source Threshold Voltage	$V_{GS} = 0V$ $T_{J} = 125^{\circ}C$ $V_{GS} = \pm 20V, V_{DS} = 0V$ $V_{GS} = V_{DS}, I_{D} = 250\mu A$	1	1.7	100 ±100	nA
o Source Leakage Current ics o Source Threshold Voltage o Source Threshold Voltage	$V_{GS} = \pm 20V, V_{DS} = 0V$ $V_{GS} = V_{DS}, I_D = 250\mu A$	1	1.7	±100	nA
ics Source Threshold Voltage Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250μA	1	1.7	1	I
Source Threshold Voltage Source Threshold Voltage		1	1.7	3	
Source Threshold Voltage		1	1.7	3	
•	$I_{-} = 250 \mu A$ referenced to $25^{\circ}C$			Ŭ	V
	$T_D = 200 \mu A$ , referenced to 20 G		-5.7		mV/°C
Drain to Source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 9.6A		9.6	14.0	
	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 8.7A		12.1	17.0	mΩ
	$V_{GS}$ = 10V, I <sub>D</sub> = 9.6A , T <sub>J</sub> = 125°C		13.5	20.0	
1 Transconductance	V <sub>DS</sub> = 5V, I <sub>D</sub> = 9.6A		35		S
cteristics					
apacitance			1000	1230	pF
Capacitance			183	255	pF
e Transfer Capacitance	f = 1MHz		118	180	pF
esistance	f = 1MHz		1.1		Ω
me ff Delay Time	<sup>—</sup> V <sub>DD</sub> = 15V, I <sub>D</sub> = 9.6A — V <sub>GS</sub> = 10V, R <sub>GEN</sub> = 6Ω		4 20	10 36	ns ns ns
			-		ns
	$V_{} = 10V_{} = 15V_{}$		18	26	nC
-			-		nC
Drain "Miller" Charge			3.9		nC
ode Characteristics					
	$V_{cc} = 0V_{cc} = 9.6A_{cc}$ (Note 2)		0.8	1.2	V
•			23	35	ns
e Recovery Charge	— I <sub>F</sub> = 9.6A, di/dt = 100A/μs		14	21	nC
	eteristics apacitance Capacitance e Transfer Capacitance esistance acteristics n Delay Time me ff Delay Time ne ate Charge Source Gate Charge Drain "Miller" Charge ode Characteristics to Drain Diode Forward Voltage e Recovery Time e Recovery Charge	I Transconductance $V_{DS} = 5V, I_D = 9.6A$ eteristics         apacitance $V_{DS} = 15V, V_{GS} = 0V, f = 1MHz$ e Transfer Capacitance $f = 1MHz$ e Transfer Capacitance $f = 1MHz$ esistance $f = 1MHz$ etteristics $f = 1MHz$ n Delay Time $V_{DD} = 15V, I_D = 9.6A$ me $V_{DD} = 15V, I_D = 9.6A$ ff Delay Time $V_{GS} = 10V, N_{GEN} = 6\Omega$ ne $I_D = 9.6A$ Source Gate Charge $V_{GS} = 10V, V_{DD} = 15V, I_D = 9.6A$ Drain "Miller" Charge $V_{GS} = 0V, I_S = 9.6A$ (Note 2)         e Recovery Time $I_F = 9.6A, di/dt = 100A/\mu s$	I Transconductance $V_{DS} = 5V$ , $I_D = 9.6A$ eteristics         apacitance $V_{DS} = 15V$ , $V_{GS} = 0V$ , f = 1MHz         e Transfer Capacitance       f = 1MHz         e sistance       f = 1MHz         eteristics       f = 1MHz         n Delay Time $V_{DD} = 15V$ , $I_D = 9.6A$ me $V_{DD} = 15V$ , $I_D = 9.6A$ ff Delay Time $V_{GS} = 10V$ , $R_{GEN} = 6\Omega$ ne $I_D = 9.6A$ Source Gate Charge $I_D = 9.6A$ Drain "Miller" Charge $V_{GS} = 0V$ , $I_S = 9.6A$ (Note 2)         e Recovery Time $I_F = 9.6A$ , di/dt = 100A/µs	I Transconductance $V_{DS} = 5V$ , $I_D = 9.6A$ 35atteristicsapacitance $V_{DS} = 15V$ , $V_{GS} = 0V$ , f = 1MHz1000Capacitancef = 1MHz118e Transfer Capacitancef = 1MHz1.1esistancef = 1MHz1.1incteristics $V_{DD} = 15V$ , $I_D = 9.6A$ 8me $V_{DD} = 15V$ , $I_D = 9.6A$ 4Me $V_{GS} = 10V$ , $R_{GEN} = 6\Omega$ 20ineate Charge $V_{GS} = 10V$ , $V_{DD} = 15V$ , $I_D = 9.6A$ 18Source Gate Charge $V_{GS} = 10V$ , $V_{DD} = 15V$ , $I_D = 9.6A$ 3.9ode Characteristics3.93.9ode Characteristics $V_{GS} = 0V$ , $I_S = 9.6A$ (Note 2)0.8e Recovery Time e Recovery Charge $I_F = 9.6A$ , di/dt = 100A/µs14	I Transconductance $V_{DS} = 5V$ , $I_D = 9.6A$ 35         eteristics       apacitance $V_{DS} = 15V$ , $V_{GS} = 0V$ , f = 1MHz       1000       1230         Capacitance       f = 1MHz       183       255         e Transfer Capacitance       f = 1MHz       118       180         esistance       f = 1MHz       1.1       118       180         esistance       f = 1MHz       1.1       111       111         incteristics       V_{DD} = 15V, $I_D = 9.6A$ 8       16         me $V_{DD} = 15V, R_{GEN} = 6\Omega$ 20       36         in Delay Time       V_{GS} = 10V, R_{GEN} = 6\Omega       20       36         in Delay Time       V_{GS} = 10V, V_{DD} = 15V, $I_D = 9.6A$ 4       10         in Delay Time       V_{GS} = 10V, V_{DD} = 15V, $I_D = 9.6A$ 2.8       2.8         in Date Charge       V_{GS} = 10V, V_{DD} = 15V, $I_D = 9.6A$ 2.8       2.8         in Drain "Miller" Charge       3.9       3.9       3.9         ode Characteristics       3.9       3.9       3.9       3.9         in Drain Diode Forward Voltage       V_{GS} = 0V, I_S = 9.6A       0.04(dt = 100A/us)       2.3       3.5

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FDMC8878 N-Channel Power Trench<sup>®</sup> MOSFET



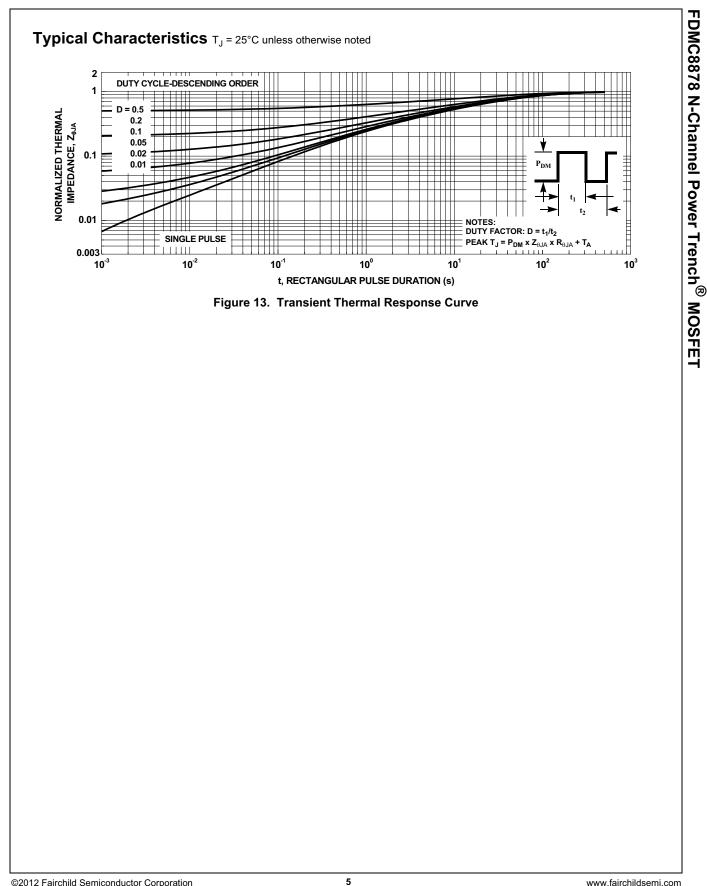
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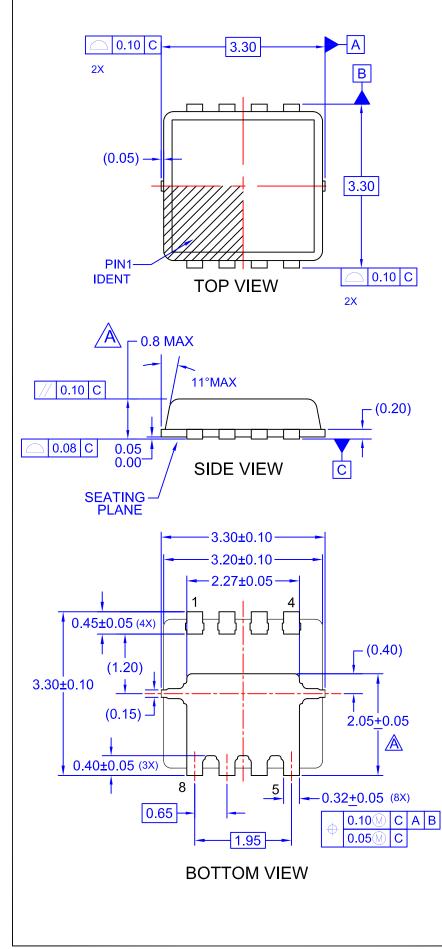


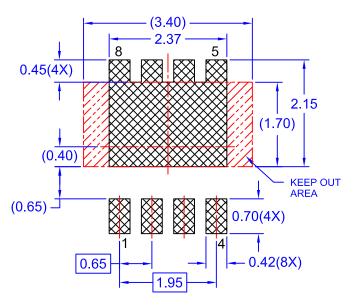
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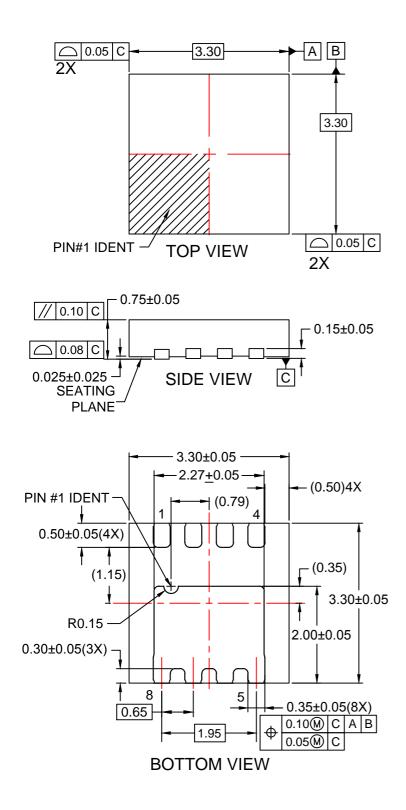


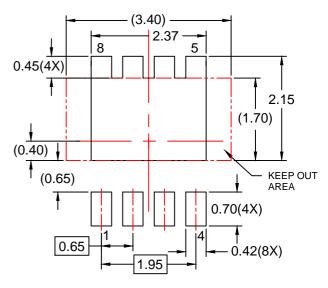
## RECOMMENDED LAND PATTERN

**NOTES:** 

- A EXCEPT AS NOTED, PACKAGE CONFORMS TO JEDEC REGISTRATION MO-240 VARIATION BA.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. SEATING PLANE IS DEFINED BY TERMINAL TIPS ONLY
- E. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.
- F. FLANGE DIMENSIONS INCLUDE INTERTERMINAL FLASH OR PROTRUSION. INTERTERMINAL FLASH OR PROTRUSION SHALL NOT EXCEED 0.25MM PER SIDE.
- G. IT IS RECOMMENDED TO HAVE NO TRACES OR VIA WITHIN THE KEEP OUT AREA.
- H. DRAWING FILENAME: MKT-MLP08Trev4.
- I. GENERAL RADII FOR ALL CORNERS SHALL BE 0.20MM MAX.







### RECOMMENDED LAND PATTERN

NOTES:

- A. DOES NOT CONFORM TO JEDEC REGISTRATION MO-229
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Srev3.



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